

Qualification Description:

The information contained herein represents proof of Reliability and Performance of the baseline process technology listed below in accordance with the Qualification Plan and test methods referenced in Section 8.0, after exposure to a variety of environments (electrical, thermal, humidity, etc) and mechanical events that may occur during installation and operational lifetime of the product. Upon conclusion of the testing the product continued to operate within specification limits, demonstrating its capability of reliable operation throughout its lifetime.

The purpose of this report is to present Qualification Test results of the of referenced process technology. The Pericom product data presented in this report qualifies all products manufactured using the exact semiconductor materials and processing techniques used in the baseline process and its off-shoot processes. The report describes the qualification test program, procedures used, criteria enforced (at the time of product validation), and the resulting test data obtained during the Qualification Test. The materials and processing techniques used in the baseline process are incorporated into the off-shoot processes, so the quality/integrity of the baseline and off-shoots (i.e.: 2PxM, 1PxM) processes will be equivalent.

Lot Background Information:

Qual Test Date:	Oct-2008 updated Jan-2014
Process Technology:	0.13um 1P8M
Foundry & Code:	MGN (G)
Qual Test Number:	QDG13006A Generic Qual for HL13G

By Ext. Process:	0.13um 1PxM
Qual Vehicle:	PI3USB103ZLE Generic PN
date codes:	Z1347GG Z1347GG Z1347GG CWR102 CWR109 CWR110

Pericom's Qualification Test Results:

Stress Test	Test Procedure	Test Conditions	Duration	# of Lots	Samples per Lot	Results Pass/Fail
Dynamic High Temp	JESD22-A108	1000 hrs 3.3V 125°C	168 hrs	3	77	77 / 0
Operating Life (DHTOL)		1000 hrs 3.3V 125°C	500 hrs	3	77	77 / 0
		1000 hrs 3.3V 125°C	1000 hrs	3	77	77 / 0
Dynamic High Temp	JESD22-A108	500 hrs 1.46/2.7V 125°C	168 hrs	3	76	76 / 0
Operating Life		500 hrs 1.46/2.7V 125°C	500 hrs	3	76	76 / 0
	ELFR based on 459 units of 168 hrs HTOL	ELFR (55C, 0.7eV, 3.3V, 60%)		100.2		
	FIT Rate based on 231 units of 1000 Hrs HTOL	FIT Rate (55C, 0.7eV, 3.3V, 60%)		33.5		
		Calculated MTBF		29,886,633		
Temp Cycle Test	JESD22-A104	-65°C to 150°C, 500cyc	100 cycles	3	77	77 / 0
		-65°C to 150°C, 500cyc	500 cycles	3	77	77 / 0
Temp Cycle Test	JESD22-A104	-65°C to 150°C, 500cyc	100 cycles	3	45	45 / 0
		-65°C to 150°C, 500cyc	500 cycles	3	45	45 / 0
High Temp Storage (HTS)	JESD22-A103	1000hrs, 0V, 150°C	168 hrs	3	77	77 / 0
		1000hrs, 0V, 150°C	500 hrs	3	77	77 / 0
		1000hrs, 0V, 150°C	1000 hrs	3	77	77 / 0
High Temp Storage (HTS)	JESD22-A103	500hrs, 0V, 150°C	168 hrs	3	22	22 / 0
		500hrs, 0V, 150°C	500 hrs	3	22	22 / 0
Latch Up Test	EIA JESD78	Report available by Device				
ESD-HBM Test	JESD22-A114	Report available by Device				

Qualification by Extension Information:

It is valid to use the reliability data of a particular process technology and apply to all products within this process technology family. All parts within the same family are designed to the same rules (layout & electrical), and manufacturing is controlled by SPC. Within a product family, a device can only be fabricated on one process technology option.

If there are any questions about this qualification, please contact Quality Support at: customerquestion@pericom.com

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